

March 2007

74ABT245 Octal Bi-Directional Transceiver with 3-STATE Outputs

Features

- Bidirectional non-inverting buffers
- A and B output sink capability of 64mA, source capability of 32mA
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50pF and 250pF loads
- Guaranteed simultaneous switching, noise level and dynamic threshold performance
- Guaranteed latchup protection
- High-impedance, glitch-free bus loading during entire power up and power down cycle
- Nondestructive, hot-insertion capability
- Disable time is less than enable time to avoid bus contention

General Description

The ABT245 contains eight non-inverting bidirectional buffers with 3-STATE outputs and is intended for busoriented applications. Current sinking capability is 64 mA on both the A and B ports. The Transmit/Receive (T/\overline{R}) input determines the direction of data flow through the bidirectional transceiver. Transmit (active HIGH) enables data from A Ports to B Ports; Receive (active LOW) enables data from B Ports to A Ports. The Output Enable input, when HIGH, disables both A and B ports by placing them in a HIGH Z condition.

Ordering Information

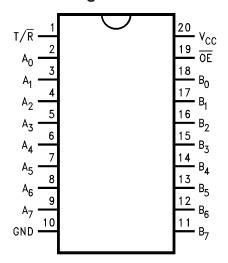
Order Number	Package Number	Package Description
74ABT245CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74ABT245CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT245CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide
74ABT245CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
74ABT245CMTCX_NL ⁽¹⁾	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering number. Pb-Free package per JEDEC J-STD-020B.

Note:

1. Device available in Tape and Reel only.

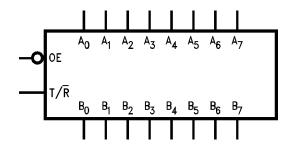
Connection Diagram



Pin Descriptions

Pin Names	Description			
ŌĒ	Output Enable Input (Active LOW)			
T/R Transmit/Receive Input				
A ₀ -A ₇	Side A Inputs or 3-STATE Outputs			
B ₀ –B ₇	Side B Inputs or 3-STATE Outputs			

Logic Symbol



Truth Table

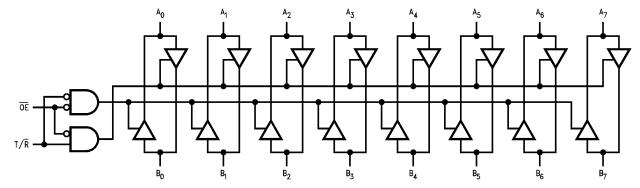
Inp	outs	
ŌĒ	T/R	Output
L	L	Bus B Data to Bus A
L	Н	Bus A Data to Bus B
Н	Х	HIGH Z State

H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

Logic Diagram



Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
T _{STG}	Storage Temperature	−65°C to +150°C
T _A	Ambient Temperature Under Bias	–55°C to +125°C
T _J	Junction Temperature Under Bias	−55°C to +150°C
V _{CC}	V _{CC} Pin Potential to Ground Pin	–0.5V to +7.0V
V _{IN}	Input Voltage ⁽²⁾	-0.5V to +7.0V
I _{IN}	Input Current ⁽²⁾	-30mA to +5.0mA
Vo	Voltage Applied to Any Output	
	Disabled or Power-off State	–0.5V to 5.5V
	HIGH State	–0.5V to V _{CC}
	Current Applied to Output in LOW State	twice the rated I _{OL} (mA)
	DC Latchup Source Current	-500mA
	Over Voltage Latchup (I/O)	10V

Note:

2. Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Rating
T _A	Free Air Ambient Temperature	–40°C to +85°C
V _{CC}	Supply Voltage	+4.5V to +5.5V
ΔV / Δt	Minimum Input Edge Rate	
	Data Input	50mV/ns
	Enable Input	20mV/ns

DC Electrical Characteristics

Symbol	Р	arameter	V _{CC}	Conditions	Min.	Тур.	Max.	Units
V _{IH}	Input HIGH	Voltage		Recognized HIGH Signal	2.0			V
V _{IL}	Input LOW \	LOW Voltage		Recognized LOW Signal			0.8	V
V _{CD}	Input Clamp	Diode Voltage	Min.	$I_{IN} = -18 \text{ mA } (\overline{OE}, T/\overline{R})$			-1.2	V
V _{OH}	Output HIGI	H Voltage	Min.	$I_{OH} = -3 \text{ mA } (A_n, B_n)$	2.5			V
			Min.	$I_{OH} = -32 \text{ mA } (A_n, B_n)$	2.0			1
V _{OL}	Output LOW	/ Voltage	Min.	$I_{OL} = 64 \text{ mA } (A_n, B_n)$			0.55	V
I _{IH}	Input HIGH	Current	Max.	$V_{IN} = 2.7V (\overline{OE}, T/\overline{R})$			1	μΑ
				$V_{IN} = V_{CC} (\overline{OE}, T/\overline{R})$			1	
I _{BVI}	Input HIGH Test	Current Breakdown	Max.	$V_{IN} = 7.0V (\overline{OE}, T/\overline{R})$			7	μA
I _{BVIT}	Input HIGH Test (I/O)	Current Breakdown	Max.	$V_{IN} = 5.5V (A_n, B_n)$			100	μA
I _{IL}	Input LOW (Current	Max.	$V_{IN} = 0.5V (\overline{OE}, T/\overline{R})$			-1	μΑ
				$V_{IN} = 0.0V (\overline{OE}, T/\overline{R})$			-1	1
V_{ID}	Input Leakage Test		0.0	$I_{ID} = 1.9 \mu A (\overline{OE}, T/\overline{R}),$ All Other Pins Grounded	4.75			V
I _{IH} + I _{OZH}	Output Leakage Current		0-5.5V	$\frac{V_{OUT} = 2.7V (A_n, B_n)}{\overline{OE} = 2.0V}$			10	μA
I _{IL} + I _{OZL}	Output Leakage Current		0-5.5V	$\begin{aligned} & V_{OUT} = 0.5V \; (A_n, \; B_n), \\ & \overline{OE} = 2.0V \end{aligned}$			-10	μA
Ios	Output Shor	t-Circuit Current	Max.	$V_{OUT} = 0.0V (A_n, B_n)$	-100		-275	mA
I _{CEX}	Output HIGI	H Leakage Current	Max.	$V_{OUT} = V_{CC}(A_n, B_n)$			50	μΑ
I _{ZZ}	Bus Drainag	ge Test	0.0	$V_{OUT} = 5.5V (A_n, B_n),$ All Others GND			100	μА
I _{CCH}	Power Supp	ly Current	Max.	All Outputs HIGH			50	μA
I _{CCL}	Power Supp	ly Current	Max.	All Outputs LOW			30	mA
I _{CCZ}	Power Supp	ly Current	Max.	$\overline{OE} = V_{CC}$, $T/\overline{R} = GND$ or V_{CC} , All Other GND or V_{CC}			50	μA
I _{CCT}	Additional	Outputs Enabled	Max.	$V_{I} = V_{CC} - 2.1V$			2.5	mA
	I _{CC} /Input	Outputs 3-STATE	1	\overline{OE} , T/ \overline{R} V _I = V _{CC} – 2.1V			2.5	mA
		Outputs 3-STATE		Data Input $V_I = V_{CC} - 2.1V$, All Others at V_{CC} or GND.			50	μA
I _{CCD}	Dynamic I _{CC} No Load		Max.	Outputs Open, \overline{OE} = GND, T/ \overline{R} = GND or V _{CC} , One Bit Toggling, 50% Duty Cycle			0.1	mA/ MHz

DC Electrical Characteristics

SOIC package.

Symbol	Parameter	V _{cc}	Conditions $C_L = 50 \text{ pF},$ $R_L = 500\Omega$	Min.	Тур.	Max.	Units
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	5.0	$T_A = 25^{\circ}C^{(3)}$		0.7	1.0	V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	5.0	$T_A = 25^{\circ}C^{(3)}$	-1.3	-1.0		V
V _{OHV}	Minimum HIGH Level Dynamic Output Voltage	5.0	$T_A = 25^{\circ}C^{(5)}$	2.7	3.1		V
V _{IHD}	V _{IHD} Minimum HIGH Level Dynamic Input Voltage		$T_A = 25^{\circ}C^{(4)}$	2.0	1.7		V
V _{ILD}	Maximum LOW Level Dynamic Input Voltage	5.0	$T_A = 25^{\circ}C^{(4)}$		0.9	0.6	V

Notes:

- 3. Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.
- 4. Max number of data inputs (n) switching. n-1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V_{ILD}) , 0V to threshold (V_{IHD}) . Guaranteed, but not tested.
- 5. Max number of outputs defined as (n). n 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

AC Electrical Characteristics

SOIC and SSOP package.

		$T_A = +25^{\circ}C$, $V_{CC} = +5V$, $C_L = 50pF$		$T_{A} = -55^{\circ}\text{C to } +125^{\circ}\text{C}, \\ V_{CC} = 4.5\text{V to } 5.5\text{V}, \\ C_{L} = 50\text{pF}$		$T_{A} = -40^{\circ}\text{C to +85°C},$ $V_{CC} = 4.5\text{V to 5.5V},$ $C_{L} = 50\text{pF}$			
Symbol	Parameter	Min.	Тур.	Max.	Min.	Max.	Min.	Max.	Units
t _{PLH}	Propagation Delay,	1.0	2.1	3.6	1.0	4.8	1.0	3.6	ns
t _{PHL}	Data to Outputs	1.0	2.4	3.6	1.0	4.8	1.0	3.6	
t _{PZH}	Output Enable Time	1.5	3.2	6.0	1.0	6.7	1.5	6.0	ns
t _{PZL}	1	1.5	3.7	6.0	2.0	7.5	1.5	6.0	
t _{PHZ}	Output Disable Time	1.0	3.6	6.1	1.7	7.4	1.0	6.1	ns
t _{PLZ}		1.0	3.3	5.6	1.7	6.5	1.0	5.6	

Extended AC Electrical Characteristics

SOIC package.

		$\begin{split} T_A &= -40^{\circ}\text{C to } +85^{\circ}\text{C}, \\ V_{CC} &= 4.5\text{V to } 5.5\text{V}, \\ C_L &= 50\text{pF}, \\ 8 \text{ Outputs Switching}^{(6)} \end{split}$		$T_A = -40$ °C to +85°C, $V_{CC} = 4.5$ V to 5.5V, $C_L = 250$ pF, 1 Output Switching ⁽⁷⁾		$T_A = -40$ °C to +85°C, $V_{CC} = 4.5$ V to 5.5V, $C_L = 250$ pF, 8 Outputs Switching ⁽⁸⁾			
Symbol	Parameter	Min.	Тур.	Max.	Min.	Max.	Min.	Max.	Units
f _{TOGGLE}	Max Toggle Frequency		100						MHz
t _{PLH}	Propagation Delay	1.5		5.0	1.5	6.0	2.5	8.5	ns
t _{PHL}	Data to Outputs	1.5		5.0	1.5	6.0	2.5	8.5	
t _{PZH}	Output Enable	1.5		6.5	2.5	7.5	2.5	9.5	ns
t _{PZL}	Time	1.5		6.5	2.5	7.5	2.5	11.0	
t _{PHZ}	Output Disable	1.0		6.5		(9)		(9)	ns
t _{PLZ}	Time	1.0		5.6					

Notes:

- 6. This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).
- 7. This specification is guaranteed but not tested. The limits represent propagation delay with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load. This specification pertains to single output switching only.
- 8. This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.
- 9. The 3-STATE delays are dominated by the RC network (500Ω , 250pF) on the output and have been excluded from the datasheet.

Skew

SOIC package.

		$T_{A} = -40^{\circ}\text{C to } +85^{\circ}\text{C},$ $V_{CC} = 4.5\text{V to } 5.5\text{V},$ $C_{L} = 50\text{pF}, 8 \text{ Outputs}$ $\text{Switching}^{(12)}$	$T_A = -40$ °C to +85°C, $V_{CC} = 4.5$ V to 5.5V, $C_L = 250$ pF, 8 Outputs Switching ⁽¹³⁾	
Symbol	Parameter	Max.	Max.	Units
t _{OSHL} ⁽¹⁰⁾	Pin to Pin Skew, HL Transitions	1.3	2.3	ns
t _{OSLH} ⁽¹⁰⁾	Pin to Pin Skew, LH Transitions	1.0	1.8	ns
t _{PS} ⁽¹⁴⁾	Duty Cycle, LH-HL Skew	2.0	3.5	ns
t _{OST} ⁽¹⁰⁾	Pin to Pin Skew, LH/HL Transitions	2.0	3.5	ns
t _{PV} ⁽¹¹⁾	Device to Device Skew, LH/HL Transitions	2.0	3.5	ns

Notes:

- 10. Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW (t_{OSHL}), LOW-to-HIGH (t_{OSLH}), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW (t_{OST}). The specification is guaranteed but not tested.
- 11. Propagation delay variation for a given set of conditions (i.e., temperature and V_{CC}) from device to device. This specification is guaranteed but not tested.
- 12. This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.)
- 13. These specifications guaranteed but not tested. The limits represent propagation delays with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.
- 14. This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.

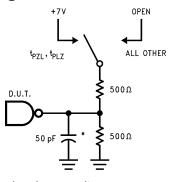
Capacitance

Symbol	Parameter	Conditions T _A = 25°C	Тур.	Units
C _{IN}	Input Capacitance	$V_{CC} = 0V (\overline{OE}, T/\overline{R})$	5.0	pF
C _{I/O} ⁽¹⁵⁾	I/O Capacitance	$V_{CC} = 5.0V (A_n, B_n)$	11.0	pF

Note:

15. $C_{I/O}$ is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.

AC Loading



*Includes jig and probe capacitance

Figure 1. Standard AC Test Load

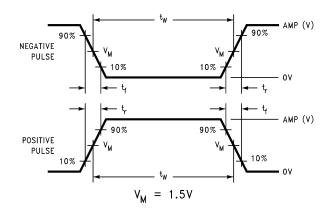


Figure 2. Test Input Signal Levels

Amplitude	Rep. Rate t _W		t _r	t _f	
3.0V	1MHz	500ns	2.5ns	2.5ns	

Figure 3. Test Input Signal Requirements

AC Waveforms

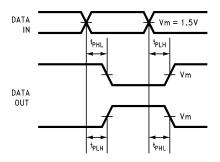


Figure 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

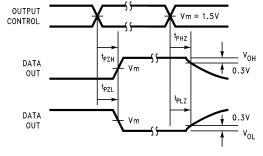


Figure 6. 3-STATE Output HIGH and LOW Enable and Disable Times

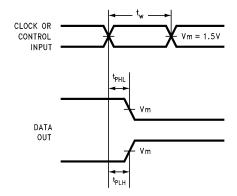


Figure 5. Propagation Delay, Pulse Width Waveforms

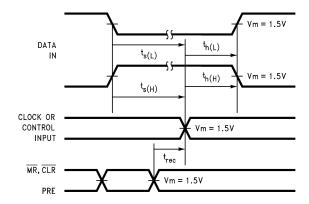
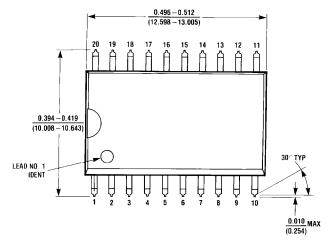
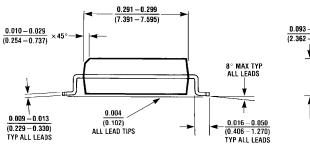


Figure 7. Setup Time, Hold Time and Recovery Time Waveforms

Physical Dimensions

Dimensions are in inches (millimeters) unless otherwise noted.





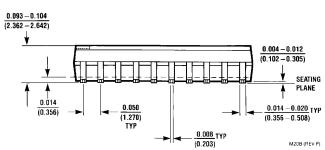
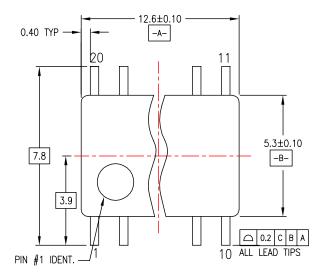
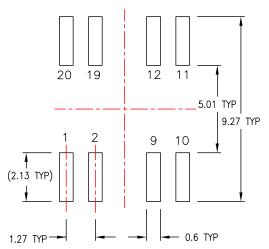


Figure 8. 20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Package Number M20B

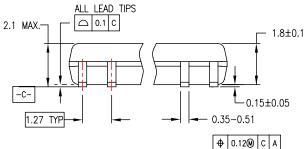
Physical Dimensions (Continued)

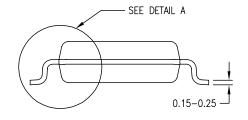
Dimensions are in millimeters unless otherwise noted.





LAND PATTERN RECOMMENDATION

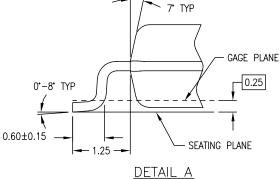




DIMENSIONS ARE IN MILLIMETERS

NOTES:

- A. CONFORMS TO EIAJ EDR-7320 REGISTRATION, ESTABLISHED IN DECEMBER, 1998.
 B. DIMENSIONS ARE IN MILLIMETERS.
 C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

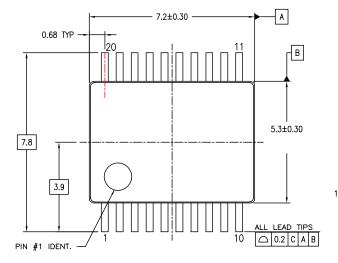


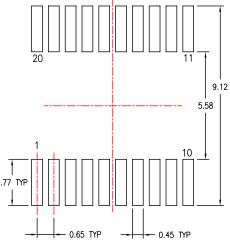
M20DREVC

Figure 9. 20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M20D

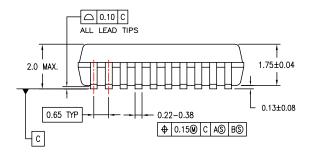
Physical Dimensions (Continued)

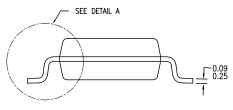
Dimensions are in millimeters unless otherwise noted.





LAND PATTERN RECOMMENDATIONS

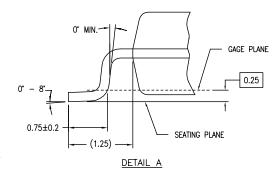




DIMENSIONS ARE IN MILLIMETERS

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-150, VARIATION AE, DATE 1/94.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D. DIMENSIONS AND TOLERANCES PER ASME Y14.5M 1994.

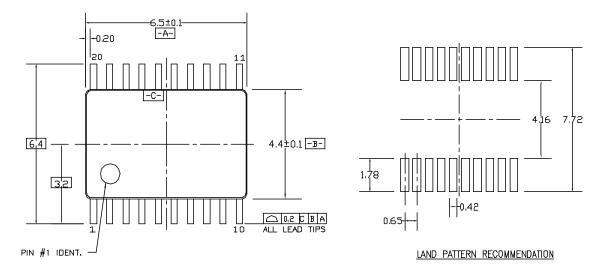


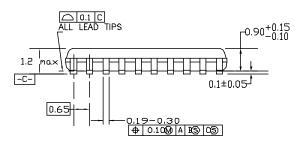
MSA20REVB

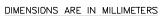
Figure 10. 20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide Package Number MSA20

Physical Dimensions (Continued)

Dimensions are in millimeters unless otherwise noted.



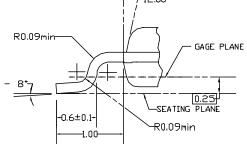




NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MD-153, VARIATION AC, REF NOTE 6, DATE 7/93.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLDS FLASH, AND TIE BAR EXTRUSIONS.
- D. DIMENSIONS AND TOLERANCES PER ANSI Y14.5M, 1982.

0.09-0.20¹



DETAIL A

MTC20REVD1

Figure 11. 20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20





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Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild Semiconductor. The datasheet is printed for reference information only.

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